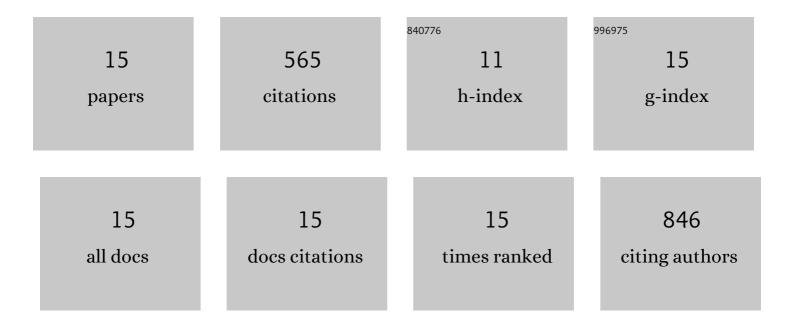
Emmanuel Cadel

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Study of solute segregation behavior at carbide–ferrite interfaces in 16MND5 welds. Journal of Nuclear Materials, 2020, 542, 152531.	2.7	1
2	Investigation of solute segregation behavior using a correlative EBSD/TKD/APT methodology in a 16MND5 weld. Journal of Nuclear Materials, 2019, 523, 434-443.	2.7	22
3	Investigation of the dependence of phosphorus segregation on grain boundary structure in Fe-P-C alloy: Nross comparison between Atom Probe Tomography and Auger Electron Spectroscopy. Applied Surface Science, 2019, 463, 203-210.	6.1	20
4	Ultrathin PECVD epitaxial Si solar cells on glass via low-temperature transfer process. Progress in Photovoltaics: Research and Applications, 2016, 24, 1075-1084.	8.1	32
5	Nanometre-scale evidence for interfacial dissolution–reprecipitation control of silicate glass corrosion. Nature Materials, 2015, 14, 307-311.	27.5	227
6	Influence of boron clustering on the emitter quality of implanted silicon solar cells: an atom probe tomography study. Progress in Photovoltaics: Research and Applications, 2015, 23, 1724-1733.	8.1	11
7	Simultaneous Quantification of Indium and Nitrogen Concentration in InGaNAs Using HAADF-STEM. Microscopy and Microanalysis, 2014, 20, 1740-1752.	0.4	20
8	Crystallographic Characterization of an Electroplated Zinc Coating Prone to Whiskers. IEEE Transactions on Components, Packaging and Manufacturing Technology, 2012, 2, 1928-1932.	2.5	6
9	Atomic scale investigation of silicon nanowires and nanoclusters. Nanoscale Research Letters, 2011, 6, 271.	5.7	12
10	Effect of die metallization layer ageing in the case of power semiconductor devices. European Journal of Electrical Engineering, 2011, 14, 569-585.	0.3	4
11	Depth resolution function of the laser assisted tomographic atom probe in the investigation of semiconductors. Journal of Applied Physics, 2009, 106, .	2.5	79
12	Phase Transformation and Segregation to Lattice Defects in Ni-Base Superalloys. Microscopy and Microanalysis, 2007, 13, 464-483.	0.4	81
13	Suzuki effect on {001} stacking faults in boron-doped FeAl intermetallics. Scripta Materialia, 2004, 51, 437-441.	5.2	16
14	Atomic Scale Investigation of Impurity Segregation to Crystal Defects. Annual Review of Materials Research, 2003, 33, 215-231.	9.3	20
15	Investigation of boron-enriched Cottrell atmospheres in FeAl on an atomic scale by three-dimensional atom-probe field-ion microscopy. Philosophical Magazine Letters, 2000, 80, 725-736.	1.2	14